


<div> <div>Search Notes</div>  </div>	<div>Application/Control No.</div> <div>10660641</div>	<div>Applicant(s)/Patent Under Reexamination</div> <div>SEGAWA ET AL.</div>
	<div>Examiner</div> <div>Carter, Aaron W</div>	<div>Art Unit</div> <div>2624</div>

SEARCHED			
Class	Subclass	Date	Examiner
382	115-127,181	5/25/07	AWC
340	5.1, 5.2, 5.52, 5.53	5/25/07	AWC
902	3	5/25/07	AWC
713	186	5/25/07	AWC

SEARCH NOTES		
Search Notes	Date	Examiner
EAST Text Search (USPAT, PGPUB) See Search History Printout	5/25/07	AWC
Inventor Name Search (See PALM Search History Printout)	5/25/07	AWC
IEEE (See Search History Printout)	5/25/07	AWC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner